

FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. <b>03500.102994.</b>	APPLICATION NO. <b>10/530,549</b>		
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			APPLICANT <b>KAZUHIKO FUKUTANI ET AL.</b>			
			FILING DATE <b>January 30, 2006</b>	GROUP <b>1743</b>		
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	<b>2005/0053773 A1</b>	<b>03/10/05</b>	<b>Fukutani et al.</b>	<b>428</b>	<b>209</b>	
	<b>2004/0043208 A1</b>	<b>03/04/04</b>	<b>Fukutani et al.</b>	<b>428</b>	<b>304.4</b>	
	<b>2004/0033339 A1</b>	<b>02/19/04</b>	<b>Fukutani et al.</b>	<b>428</b>	<b>137</b>	
	<b>6,602,620 B1</b>	<b>08/05/03</b>	<b>Kikitsu et al.</b>	<b>428</b>	<b>694 T</b>	
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FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
JP	<b>2001-261376</b>	<b>09/26/01</b>	<b>Japan</b>			<b>Abstract</b>
JP	<b>9-157062</b>	<b>06/17/97</b>	<b>Japan</b>			<b>Abstract and English Translation</b>
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)						
	<b>C.D. Adams et al., "Monte Carlo Simulation of Phase Separation During Thin-Film Codeposition," J. Appl. Phys. 74 (3), 1 August 1993, American Institute of Physics, pp. 1707-1715.</b>					
	<b>C.D. Adams et al., "Transition from Lateral to Transverse Phase Separation During Film Co-deposition," Appl. Phys. Lett. 59 (20), 11 November 1991, American Institute of Physics, pp. 2535-2537.</b>					
	<b>C.D. Adams et al., "Phase Separation During Co-deposition of Al-Ge Thin Films," J. Mater. Res., Vol. 7, No. 3, March 1992, Materials Research Society, pp. 653-667</b>					
	<b>M. Atzman et al., "Phase Separation During Film Growth," J. Appl. Phys. 42 (2), 15 July 1992, American Institute of Physics, pp. 442-446.</b>					
	<b>M. Jacobs et al., "Unbalanced Magnetron Sputtered Si-Al Coatings: Plasma Conditions and Film Properties Versus Sample Bias Voltage," Surface and Coatings Technology 116-119 (1999) pp. 738-741.</b>					
EXAMINER	DATE CONSIDERED <i>7/5/2007</i>					

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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